




<b>Issue Classification</b> 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/788,667	FERIANZ ET AL.	
	Examiner	Art Unit	
	Hiep Nguyen	2816	

ISSUE CLASSIFICATION									
ORIGINAL				CROSS REFERENCE(S)					
CLASS	SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
327	108			327	110				
INTERNATIONAL CLASSIFICATION				326	82	83			
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HIEP NGUYEN 03.03.06 (Assistant Examiner) (Date)		 <b>TUAN T. LAM</b> PRIMARY EXAMINER (Primary Examiner)	Total Claims Allowed: 25	
 (Legal Instruments Examiner) (Date)			O.G. Print Claim(s) 1	O.G. Print Fig. 2,5

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
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